

September 2010

# FDMC4435BZ

# P-Channel Power Trench<sup>®</sup> MOSFET -30 V, -18 A, 20 m $\Omega$

## **Features**

- Max  $r_{DS(on)}$  = 20 m $\Omega$  at  $V_{GS}$  = -10 V,  $I_D$  = -8.5 A
- Max  $r_{DS(on)}$  = 37 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -6.3 A
- Extended V<sub>GSS</sub> range (-25 V) for battery applications
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability
- HBM ESD protection level >7 kV typical (Note 4)
- 100% UIL Tested
- Termination is Lead-free and RoHS Compliant

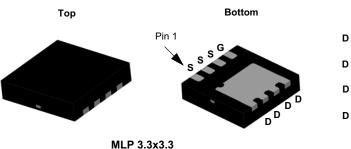
# **General Description**

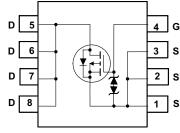
This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

#### **Applications**

- High side in DC DC Buck Converters
- Notebook battery power management
- Load switch in Notebook







# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Parameter			Units
V <sub>DS</sub>	Drain to Source Voltage			-30	V
V <sub>GS</sub>	Gate to Source Voltage			±25	V
I <sub>D</sub>	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		-18	
	-Continuous (Silicon limited) T <sub>C</sub> = 25 °C			-32	^
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-8.5	Α
	-Pulsed			-50	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	24	mJ
D	Power Dissipation	T <sub>C</sub> = 25 °C		31	14/
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.3	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC4435BZ	FDMC4435BZ	MLP 3.3X3.3	13 "	12 mm	3000 units

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# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0 V	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, referenced to 25 °C		- 22		mV/°C
l	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24 V,			-1	μА
IDSS	Zelo Gale Vollage Dialii Guiletti	$V_{GS} = 0 V$ , $T_J = 125 °C$			-100	μΛ
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

## On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1.0	-1.9	-3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 μA, referenced to 25 °C		5.3		mV/°C
		$V_{GS} = -10 \text{ V}, I_D = -8.5 \text{ A}$		15	20	
r	Static Drain to Source On Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -6.3 \text{ A}$		23	37	mΩ
r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS}$ = -10 V, $I_D$ = -8.5 A, $T_J$ = 125 °C		21	28	11122	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = -5 V, I <sub>D</sub> = -8.5 A		24		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 45 V V - 0 V	1540	2045	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = -15 V, V <sub>GS</sub> = 0 V, f = 1 MHz	295	395	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	260	385	pF
$R_g$	Gate Resistance	f = 1 MHz	5		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		10	20	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = -15 V, I <sub>D</sub> = -8.5 A,	6	12	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = -10 V, $R_{GEN}$ = 6 $\Omega$	34	55	ns
t <sub>f</sub>	Fall Time		20	36	ns
$Q_q$	Total Gate Charge	V <sub>GS</sub> =0V to -10V	33	46	nC
$Q_q$	Total Gate Charge	$V_{GS} = 0 \text{ V to } -4.5 \text{ V}$ $V_{DD} = -15 \text{ V},$	17	24	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = -8.5 A	5		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		9		nC

## **Drain-Source Diode Characteristics**

	Source to Drain Diode, Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -8.5 \text{A}$ (Note 2)	0.92	92 1.5	V
	$V_{GS} = 0 \text{ V}, I_{S} = -1.9 \text{ A}$ (Note 2)	0.75	1.2	V	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = -8.5 A, di/dt = 100 A/μs	22		ns
Q <sub>rr</sub>	Reverse Recovery Charge	η <sub>F</sub> – -6.5 A, αι/αι – 100 A/μs	11		nC

NOTES

<sup>1.</sup> R<sub>0,IA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,IC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a. 53 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b.125 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0 %.
- 3.  $E_{AS}$  of 24 mJ is based on starting  $T_{J}$  = 25 °C, L = 1 mH,  $I_{AS}$  = -7 A,  $V_{DD}$  = -27 V,  $V_{GS}$  = -10 V. 100% test at L = 3 mH,  $I_{AS}$  = -4 A.
- 4. The diode connected between the gate and source servers only as protection against ESD. No gate overvoltage rating is implied.

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

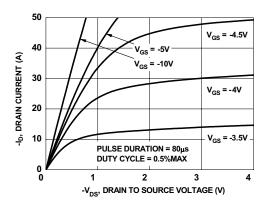


Figure 1. On-Region Characteristics

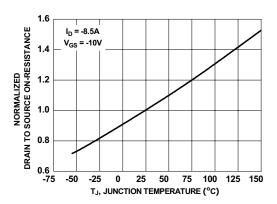


Figure 3. Normalized On-Resistance vs Junction Temperature

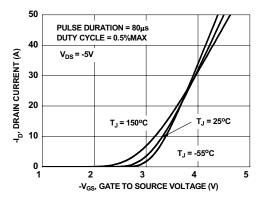


Figure 5. Transfer Characteristics

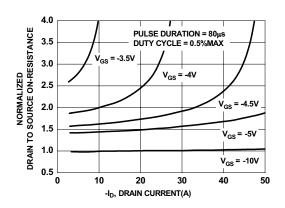


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

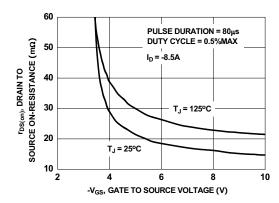


Figure 4. On-Resistance vs Gate to Source Voltage

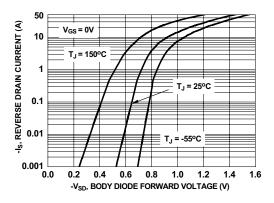


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

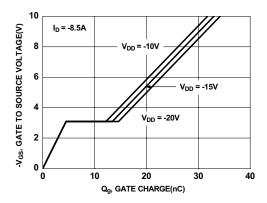


Figure 7. Gate Charge Characteristics

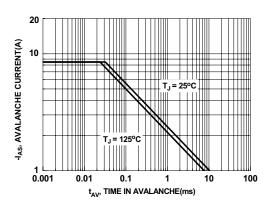


Figure 9. Unclamped Inductive Switching Capability

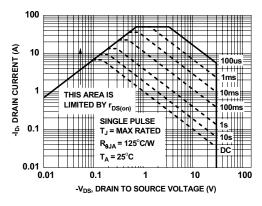


Figure 11. Forward Bias Safe Operating Area

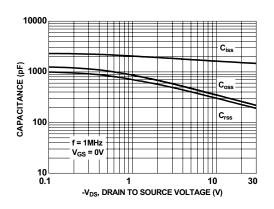


Figure 8. Capacitance vs Drain to Source Voltage

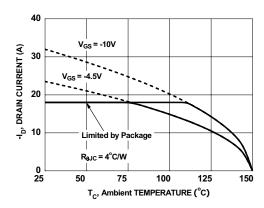


Figure 10. Maximum Continuous Drain Current vs Case Temperature

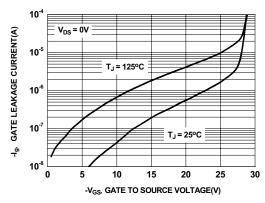


Figure 12. Igss vs Vgss



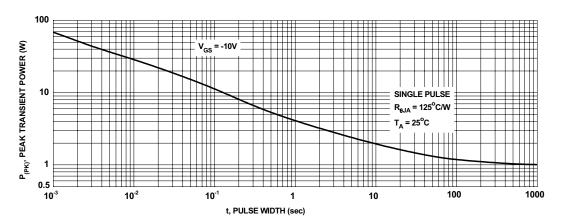


Figure 13. Single Pulse Maximum Power Dissipation

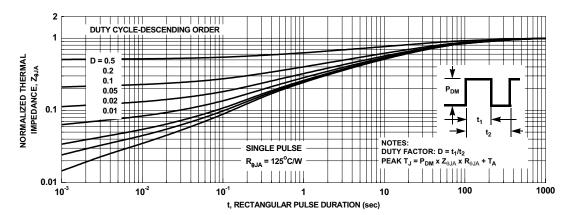
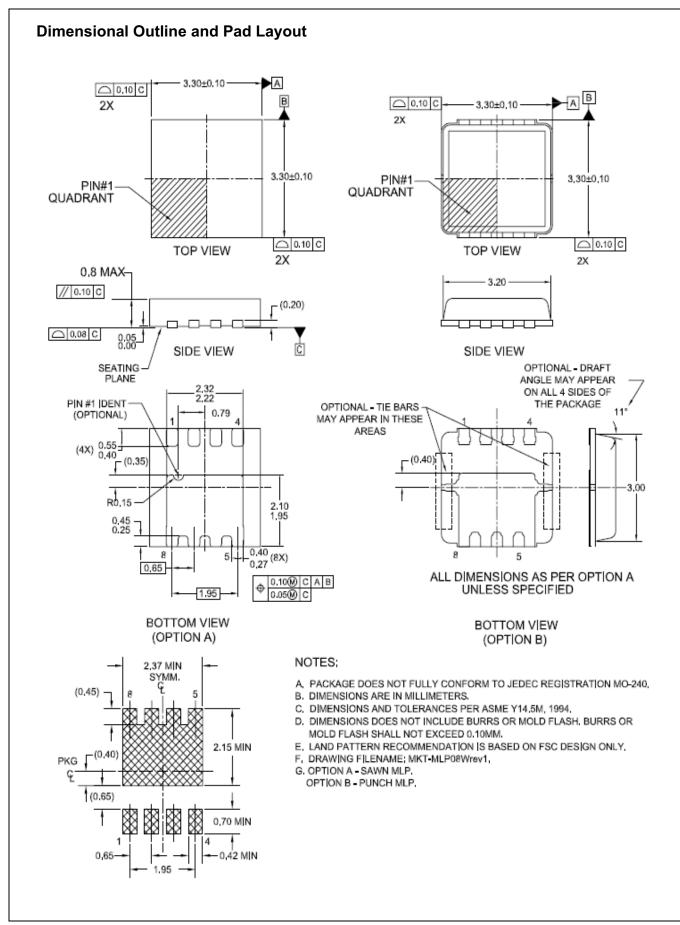


Figure 14. Transient Thermal Response Curve







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